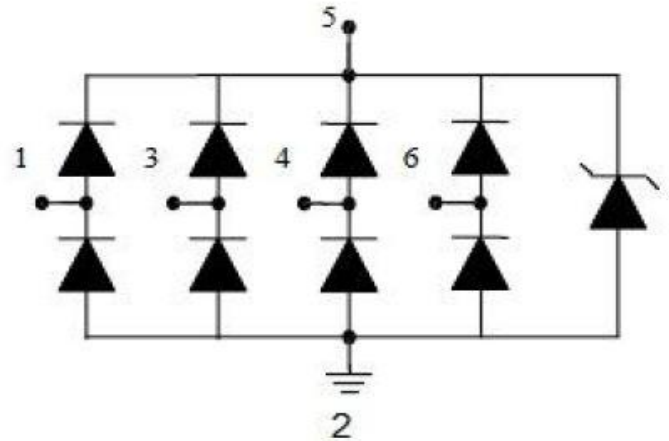
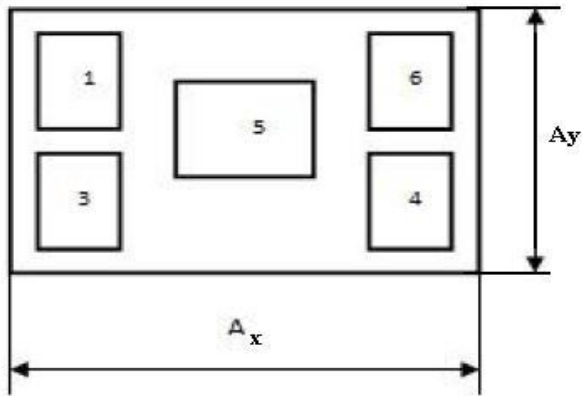


Ultra Low Capacitance TVS Diode



Pin 2 – back side – GND.

Mechanical date: $A_x=600\text{ um}$, $A_y=420\text{um}$,

Pad Size for Pin 1, 3, 4, 6 - $85 * 95\text{ um}$.

Pad Size for Pin 5 - $270 * 105\text{ um}$.

Chip thickness: a) $138 \pm 12\text{um}$.
b) $470 \pm 20\text{ um}$

Scribe Line width - 60um .

Top Metal: Al - for wire bonding

Back side - Anode: a) Ti-Ni-Ag for soldering
b) without metallization.

Schematic and pinning diagram.

Probing: a) **sampling testing:** no bad dice inking
guaranteed good dice quantity $\geq 93\%$.
b) **100% testing (if agreed with customer):**
wafer mapping data
no bad dice inking

Limiting values

Parameter	Symbol	Conditions	Value	Unit
Reverse Stand-off voltage	V_{RWM}	-	5	V
Peak Pulse Power	P_{pp}	$t_p=8/20\text{us}$	150**	W
Peak Pulse Current	I_{pp}	$t_p=8/20\text{us}$	5**	A
Electrostatic Discharge	V_{ESD}	IEC 61000-4-2, level 4.	>8 (Contact); >15 (Air).	kV
Max.junction temperature	T_j^*	-	+150	$^{\circ}\text{C}$

Characteristics ($T_j=25^{\circ}\text{C}$)

PARAMETER	CONDITIONS	MIN	TYP.	MAX.	UNIT
Breakdown voltage	$I_R=1\text{mA}$. Pin 5 to Pin 2.	6,1	8,0	8,5	V
Reverse leakage current	$V=+5\text{V}$. Pin 1, 3, 4, 5, 6 to Pin 2. $V=-5\text{V}$. Pin 1, 3, 4, 6 to Pin 5.	-	-	0,9	μA
Forward voltage	$I_F=15\text{mA}$. Pin 2 to Pin 1, 3, 4, 5, 6.	-	-	0,95	V
Clamping Voltage	$I_{pp}=1.0\text{A}$, $t_p=8/20\text{us}$ Pin 1, 3, 4, 6 to Pin 2.	-	-	15**	V
Clamping Voltage	$I_{pp}=5.0\text{A}$, $t_p=8/20\text{us}$ Pin 1, 3, 4, 6 to Pin 2.	-	-	28**	V
Capacitance. Any I/O pin to Ground	$V_R=0\text{ V}$, $f=1\text{MHz}$	-	-	0,8	pF
Capacitance. Any I/O pin to I/O	$V_R=0\text{ V}$, $f=1\text{MHz}$	-	-	0,4	pF

* $T_j=T_a+R_{th(j-a)} \times (P_f+P_r)$, where $R_{th(j-a)}$ – thermal resistance, P_f – forward power dissipation, P_r – revers power dissipation

**For Device testing